



Finding the Needle in the Haystack on the Use of Al in Defect Analysis

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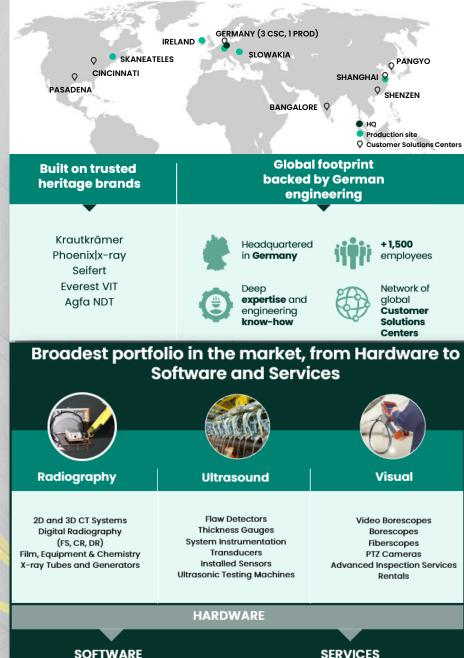
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Your partner for industrial inspection solutions.

- o Global leader in non-destructive testing solutions
- Ensuring safety, quality and productivity for over 10,000 customers worldwide
- o 125+ years of NDT experience
- o Driving insights and innovations from data
- Making sure that cars start reliably, planes fly safely, and phones turn on smoothly. Every time.



story Flow of the

Why inspect?

Recognizing defects

Automating the analysis - how is it done?

ADR, AI, ML and Neural Networks

Let's make it practical

Case studies

Wrap-up



Why inspect?

- Make things better, faster
- Improve performance, life

Waste and risk reduction



Implementation cost



NDE/QC:

- Cost
- Structural
- Material defects
- Dimensional/Metrology
- Mfg. equipment trending

In-service:

- Life
- Integrity
- Reliability



Examples: failing airbags, blown aircraft engines, burning EV's

ACQUIRE

inspection data

ANALYZE to gain insight

ACT on insights

In general: Greater risk, greater desire for inspections (quality systems)

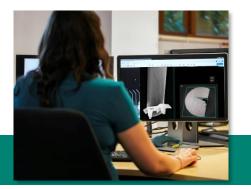


Interpreting non-destructive data

Logistical challenges facing NDE ✓ Resource burden: skilled, certified

- Cost and perception
- Aging workforce
- Need for speed
- Data retention
- Data flow



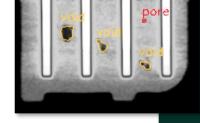




Automated Analysis:



- Speed
- Quality
- Resource
- Comprehensive: NDE 4.0



Considerations:

- Scope
- Performance
- Quality system
- Automate or assist?
- Timing
- Data

- Integration
- Validation and acceptance

Technical challenges of NDE

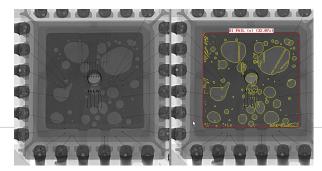
- ✓ Human performance
- Tech Plans, Maintenance Manuals

ACQUIRE

inspection data



ACT on insights



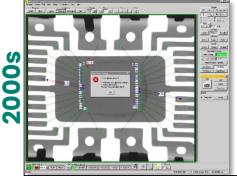


Our history of ADR...



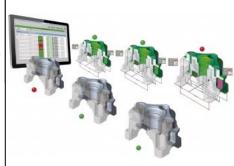
Seifert SABA, world's first commercial X-ray ADR...

Automatic 2D ADR for auto safety parts



Phoenix X-ray XE² ADR targeting electronics...

Extensively adopted and used for PCB /solder ball inspection



Speed|ADR

High speed 3D ADR for helically scanned CT part



2020s

Visual ADR

Still and video image based ADR

X|approver

ADR for consumer battery defects

InspectionWorks

Cloud-based data ADR and data mgmt.

Waygate Technologies has been a pioneer in enhanced inspection techniques for 125 years and has evolved ADR for the last 30 years, starting with rudimentary rules based and pattern recognition techniques through to the most sophisticated machine learning and AI enhanced algorithms.



Outcome restricted by your input (GIGO)

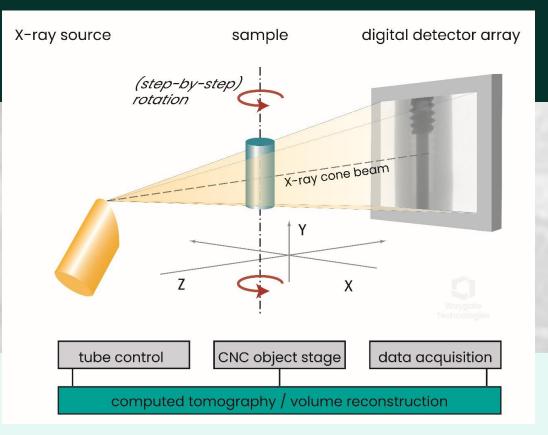
Relevant questions to consider:

- · What does your data look like?
- Has acquisition been optimized?
- · Detection entitlement?
- Challenge of detection task?
- Knowledge of defect scope / impact?
- · Binary? Regional dependencies?

Al-specific:



- AI = data
- Capture all defects?
- How frequently encountered?
- What is current and desired performance?





Detection Approaches: Al, ML, and DL

Rules-based morphology

- Pros: Predictable, understood, lower data dependency, allows regional variations
- Cons: Potentially slow, need for descriptive rules, 'fixed' solution

Dictionary Learning

- Model-based anomaly detection
- Pros: Predictable, Fail-safe
- Cons: Data dependency

CNNs, FFNNs, ...

- Pros: Easy to apply to variety of detection tasks
- Cons: Data dependency, false call risk, not common for regional variation
- E.g. layered CNNs, YOLOvX, FFNN's, ...

Auto-encoders

- Model-based anomaly detection
- Pros: Predictable, Fail-safe
- Cons: Data dependency

Unsupervised approaches

- Find anomalies
- · Addresses annotation burden

Statistical/Correlation

- Pros: Predictable, straightforward
- Cons: Data dependency; false call risk upon changes in data

Principle Component Analysis

Dimensionality reduction based

Generative Adversarial Networks

- DL comprised of two networks that try to outdo each other
- Promising
- Reduce data dependencies

Background Subtraction

Pros: Simple
 Unstable to changes, lower performance

Support Vector Machine

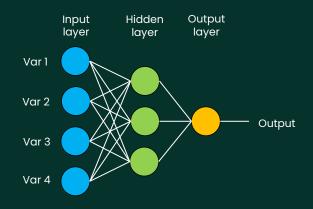
Aimed at classification





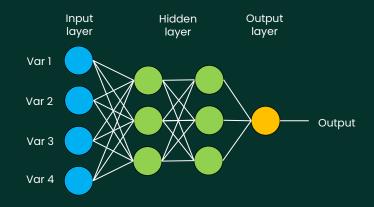
Neural Networks

Simple network:

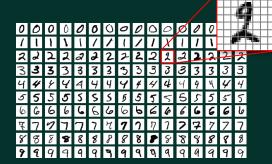


Neural networks:

- Input, output, and hidden layers
- Layers of nodes
- Combinations and weights
- Analogy to neurons



Classification example:



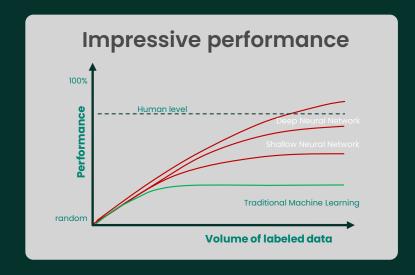
How would you design software to recognize handwritten characters?

- Image matrix
- · Limited output
- Variation on input
- Convolutions

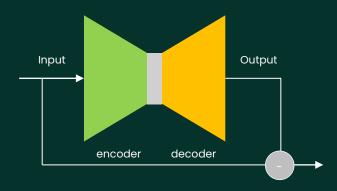


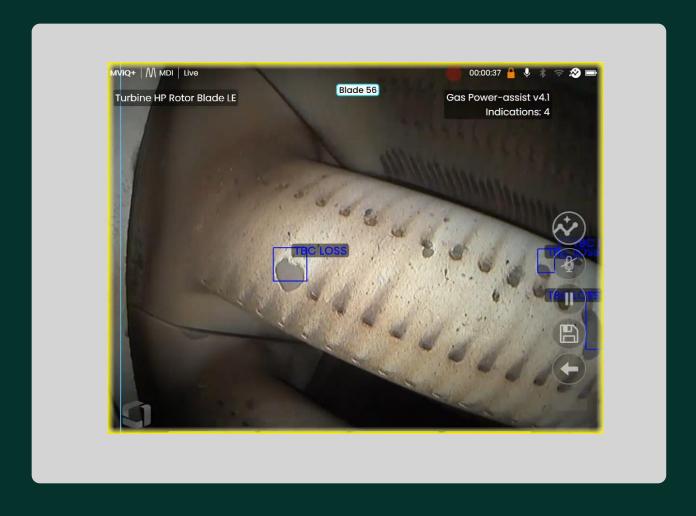
"THE MNIST DATABASE of handwritten digits"

Neural Networks



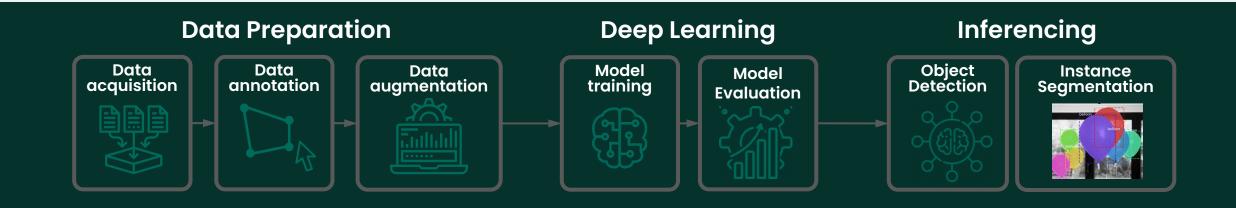
Magic in stacking networks, e.g.:







Let's make it practical... almost

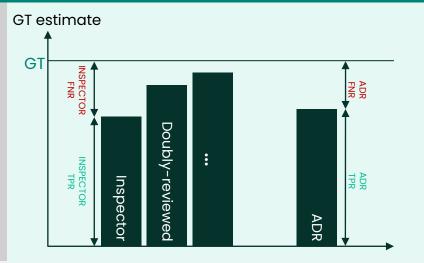


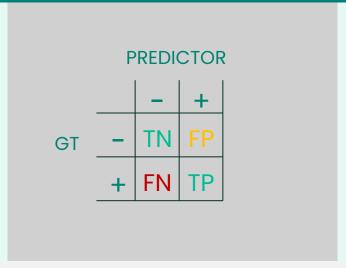
Performance Concepts:

applicable to any inspection modality

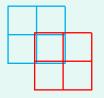
BEFOREHAND:

- GT
- TPR, FPR
- IoU





DID WE GET IT?

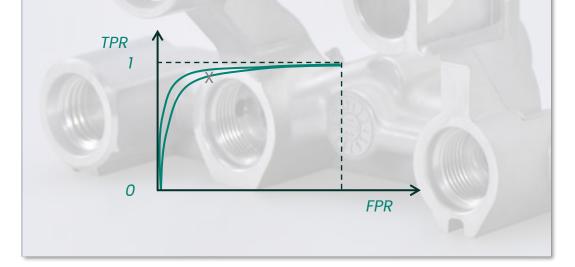




Let's make it practical: Using ADR

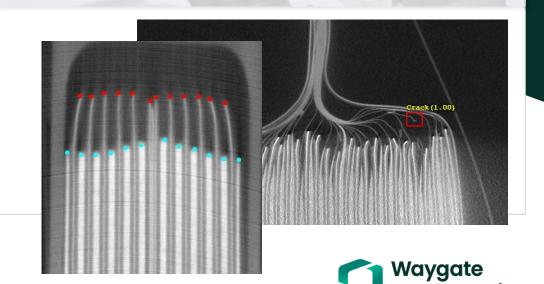
Validate performance (inferencing): Detection rates: ROC charts Cycle time

- Cycle time
- Failure modes
- Stability



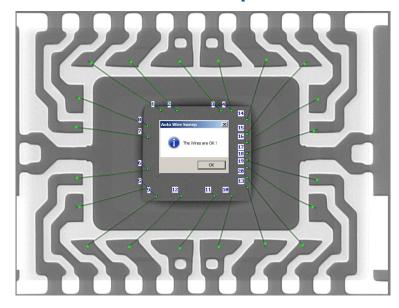
Impact on NDE:

- Perception across roles: business, quality, NDE personnel
- Excitement and fears: transient & expectations
- Big-picture: NDE 4.0 feedback loops, lifing, etc.
- Increased quality and expectations
- Impact to inspectors
- Capture of information ("blockchain")



Let's make it really practical: hardware engineering examples

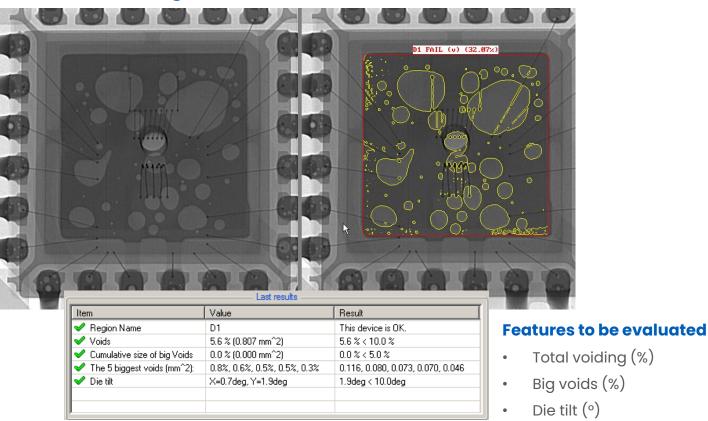
X|act: Wire Sweep



Defects to be identified

- Short wire short distance between two wires
- Messy wire wire with unexpected position
- Residual wire odd or unsuspected wire
- Wire sweep

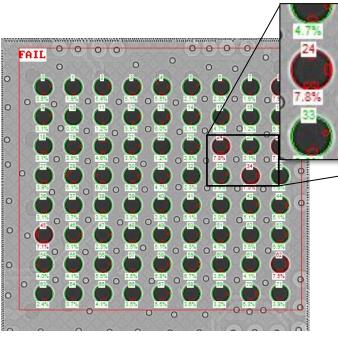
X|act: Voiding Calculation (VC)





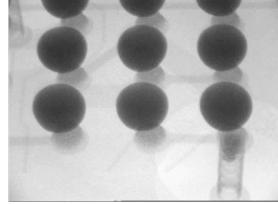
Let's make it really practical: hardware engineering examples

X|act: Ball Grid Array (BGA, µBGA, FC)



Features:

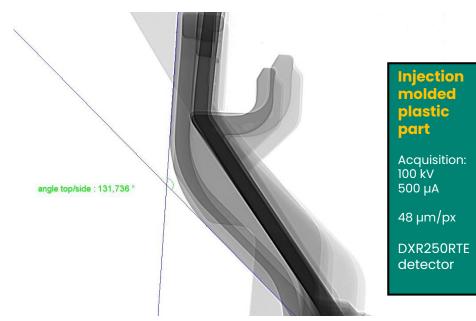
- Form deviation
- Position offset
- Area deviation
- Missing balls
- Voiding (%)
- Diameter



20x time-lapse film shows reflow process.



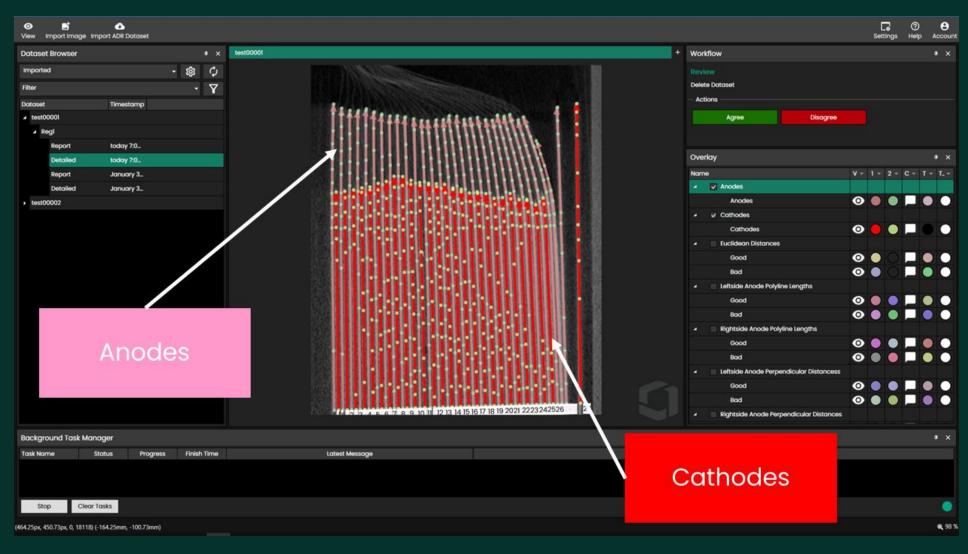
X|act: Geometric fitting



- · Measurement of an angle from side view
- All structures of the part are overlaid in the X-ray image
- Automatic measurements with flexible, programmable X-ray image evaluation routines (XE²)



Let's make it really practical: *Teachable ADR*



Xapprover:

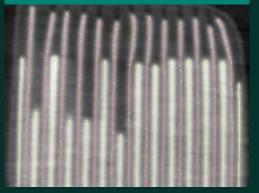
Al software platform for X-ray and CT



Let's make it really practical: X/approver for battery inspection

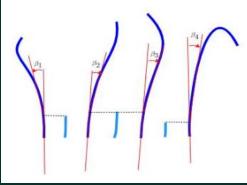


Battery Overhang



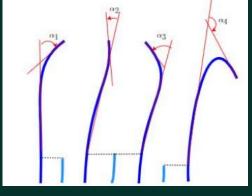
Cathode and anode position

Overhang Exit Angle



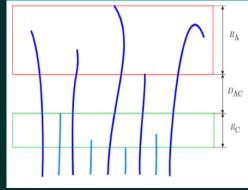
Measure Anode angle, Highest Cathode length neighbor

Overhang Bend Angle



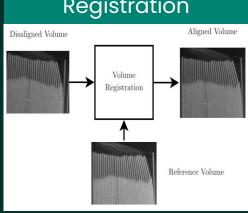
Measure Anode Bending angle

Overhang Tolerance



Electrode Range/Tolerance

Volumetric Registration



Align volume 2D & 3D



Take-home message

- Inspections / Measurements for QA
- Assisted/Automated Defect Recognition
 - -Defects
 - Anomalies
 - -Measurements
- There is more to ADR than DL
 - -AI/ML/DL
 - -Performance Metrics
 - -Impact
- Novel AI has opened the door to exciting applications in NDT





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